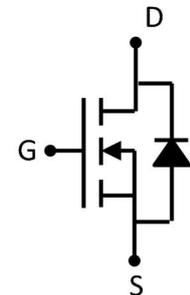


AP200N04D

N-Channel Enhancement Mosfet

Feature

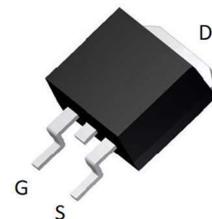
- 40V,160A
 $R_{DS(ON)} < 2.8m\Omega @ V_{GS}=10V$ TYP:2.4 m Ω
 $R_{DS(ON)} < 4.0m\Omega @ V_{GS}=4.5V$ TYP:3.2m Ω
- Advanced Trench Technology
- Lead free product is acquired
- Excellent $R_{DS(ON)}$ and Low Gate Charge



Schematic diagram

Application

- PWM applications
- Load Switch
- Power management



TO-263 top view

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity (PCS) |
|----------------|-----------|----------------|-----------|------------|----------------|
| 200N04D | AP200N04D | TO-263 | 13 Inch | - | 800 |

ABSOLUTE MAXIMUM RATINGS ($T_a=25^{\circ}C$ unless otherwise noted)

| Parameter | Symbol | Value | Unit |
|---|-----------------|-----------|---------------|
| Drain-Source Voltage | V_{DS} | 40 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current ($T_a=25^{\circ}C$) | I_D | 160 | A |
| Continuous Drain Current ($T_a=100^{\circ}C$) | I_D | 112 | A |
| Pulsed Drain Current ⁽¹⁾ | I_{DM} | 520 | A |
| Singel Pulsed Avalanche Energy ⁽²⁾ | E_{AS} | 260 | mJ |
| Power Dissipation | P_D | 180 | W |
| Thermal Resistance from Junction to Case ⁽⁴⁾ | $R_{\theta JC}$ | 0.83 | $^{\circ}C/W$ |
| Junction Temperature | T_J | 150 | $^{\circ}C$ |
| Storage Temperature | T_{STG} | -55~ +150 | $^{\circ}C$ |

MOSFET ELECTRICAL CHARACTERISTICS($T_a=25^{\circ}\text{C}$ unless otherwise noted)

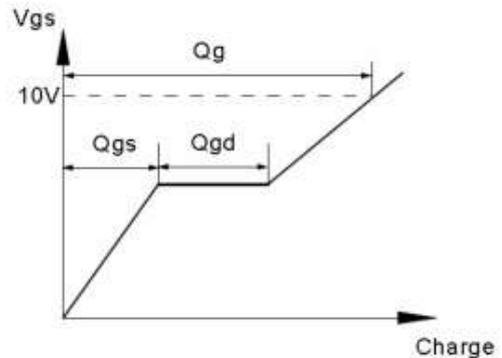
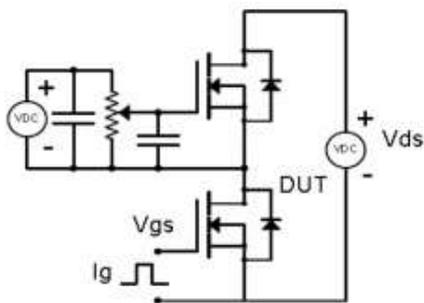
| Parameter | Symbol | Test Condition | Min | Type | Max | Unit |
|---|---------------|---|-----|-------|-----------|------------|
| Static Characteristics | | | | | | |
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $V_{GS} = 0V, I_D = 250\mu A$ | 40 | - | - | V |
| Zero gate voltage drain current | I_{DSS} | $V_{DS} = 40V, V_{GS} = 0V$ | - | - | 1 | μA |
| Gate-body leakage current | I_{GSS} | $V_{GS} = \pm 20V, V_{DS} = 0V$ | - | - | ± 100 | nA |
| Gate threshold voltage ⁽³⁾ | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = 250\mu A$ | 1 | 1.5 | 2.2 | V |
| Drain-source on-resistance ⁽³⁾ | $R_{DS(on)}$ | $V_{GS} = 10V, I_D = 50A$ | - | 2.4 | 2.8 | m Ω |
| | | $V_{GS} = 4.5V, I_D = 30A$ | - | 3.2 | 4.0 | |
| Dynamic characteristics | | | | | | |
| Input Capacitance | C_{iss} | $V_{DS} = 20V, V_{GS} = 0V, f = 1MHz$ | - | 6260 | - | pF |
| Output Capacitance | C_{oss} | | - | 523 | - | |
| Reverse Transfer Capacitance | C_{rss} | | - | 727 | - | |
| Switching characteristics | | | | | | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD} = 20V, I_D = 30A, R_L = 1\Omega$ $V_{GS} = 10V, R_G = 3\Omega$ | - | 16.8 | - | ns |
| Turn-on rise time | t_r | | - | 38.1 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 116.4 | - | |
| Turn-off fall time | t_f | | - | 33.4 | - | |
| Total Gate Charge | Q_g | $V_{DS} = 20V, I_D = 30A,$ $V_{GS} = 10V$ | - | 129.6 | - | nC |
| Gate-Source Charge | Q_{gs} | | - | 20.3 | - | |
| Gate-Drain Charge | Q_{gd} | | - | 27.4 | - | |
| Source-Drain Diode characteristics | | | | | | |
| Diode Forward voltage ⁽³⁾ | V_{DS} | $V_{GS} = 0V, I_S = 10A$ | - | - | 1.2 | V |
| Diode Forward current ⁽⁴⁾ | I_S | | - | - | 160 | A |
| Body Diode Reverse Recovery Time | t_{rr} | $T_J = 25^{\circ}, I_F = 30A, di/dt = 100A/\mu s$ | | 23.5 | | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | $T_J = 25^{\circ}, I_F = 30A, di/dt = 100A/\mu s$ | | 12.8 | | nc |

Notes:

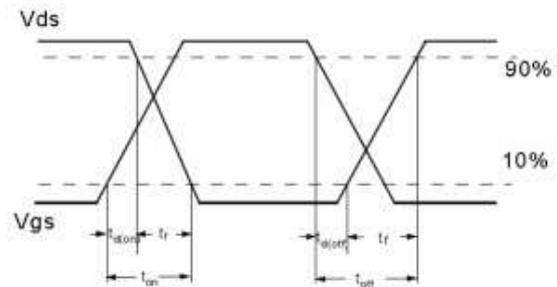
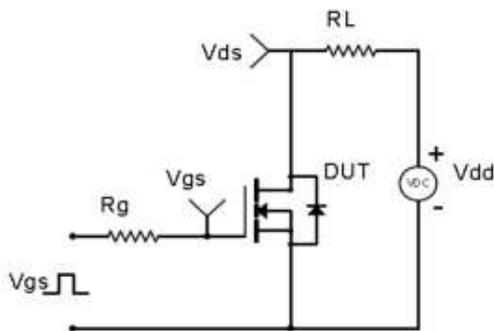
1. Repetitive Rating: pulse width limited by maximum junction temperature
2. EAS Condition: $T_J = 25^{\circ}\text{C}, V_{DD} = 20V, R_G = 25\Omega, L = 0.5\text{mH}$
3. Pulse Test: pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
4. Surface Mounted on FR4 Board, $t \leq 10\text{ sec}$

Test Circuit & Waveform

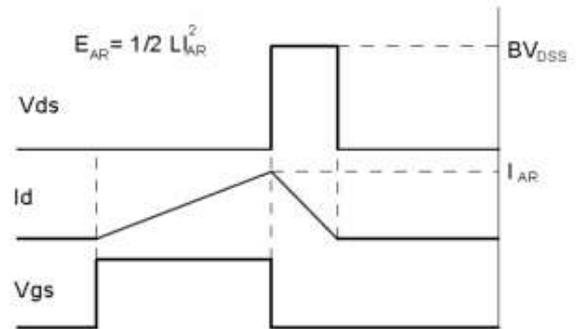
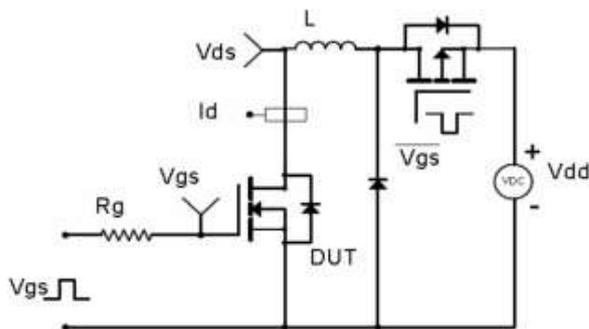
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

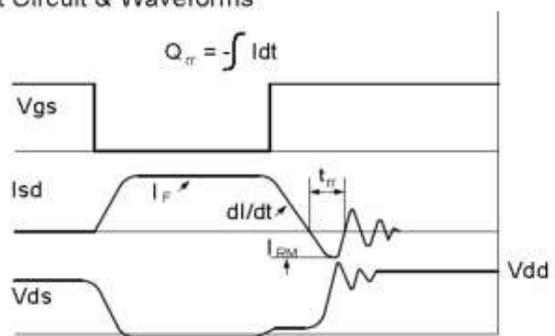
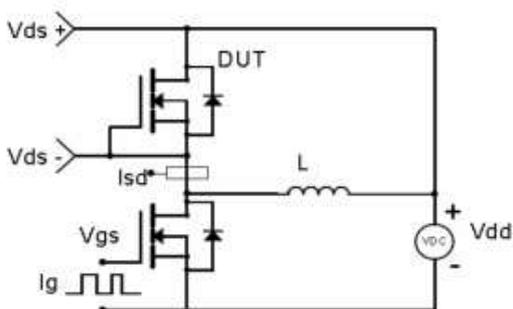


Fig1. Power Dissipation Derating Curve

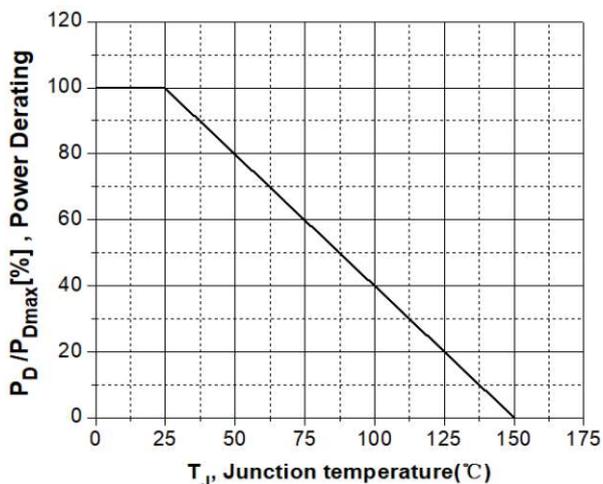


Fig2. Avalanche Energy Derating Curve vs. Junction Temperature

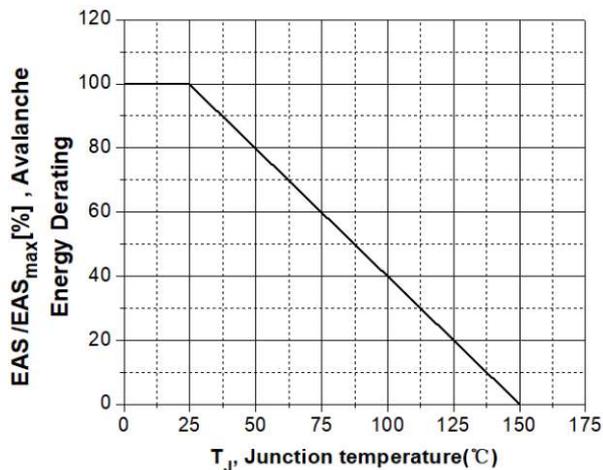


Fig3. Typical Output Characteristics @ $T_J = 125^\circ\text{C}$

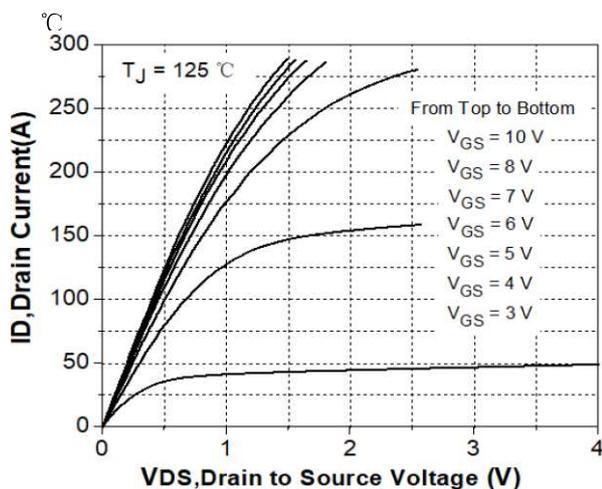


Fig4. Transconductance vs. Drain Current @ $T_J = -25/25/75/125^\circ\text{C}$

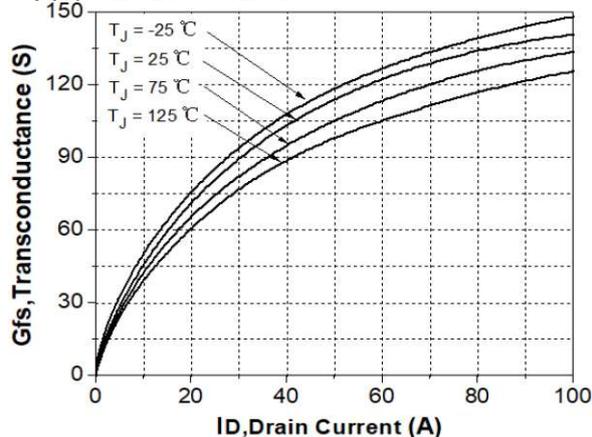


Fig5. Typical Transfer Characteristics

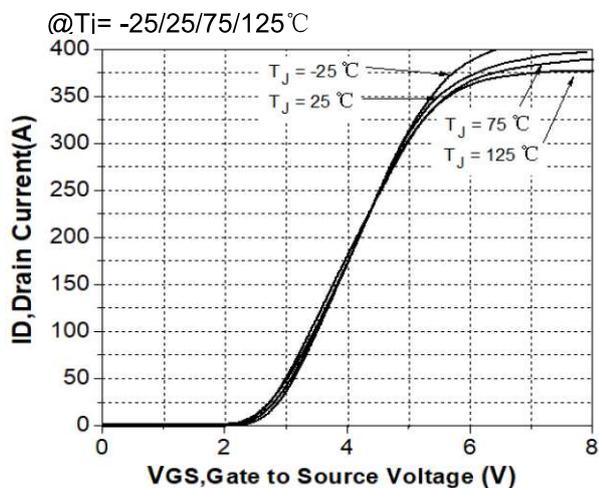


Fig6. Static Drain - Source On - State Resistance vs. Drain Current @ $T_J = -25^\circ\text{C}$

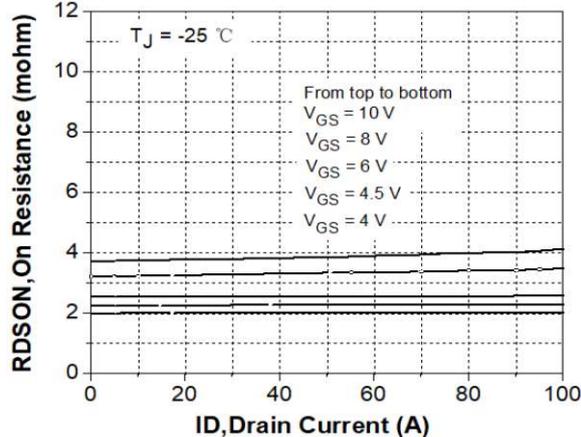


Fig7. Static Drain - Source On - State Resistance vs. Drain Current @Tj= 25 °C

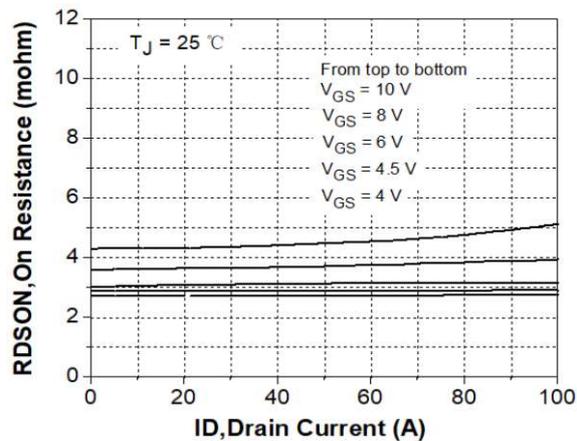


Fig8. Static Drain - Source On - State Resistance vs. Drain Current @Tj= 75 °C

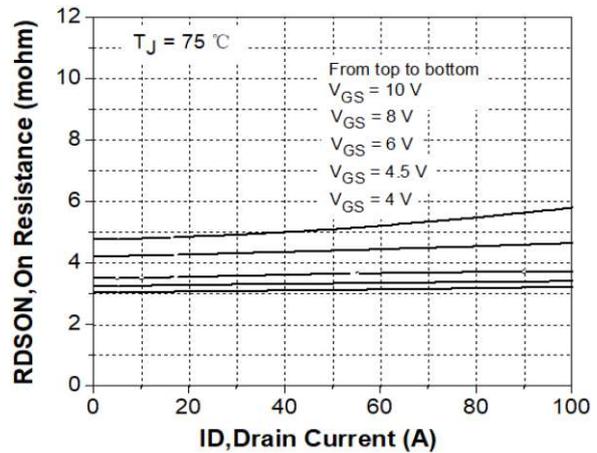


Fig9. Static Drain - Source On - State Resistance vs. Drain Current @Ti= 125 °C

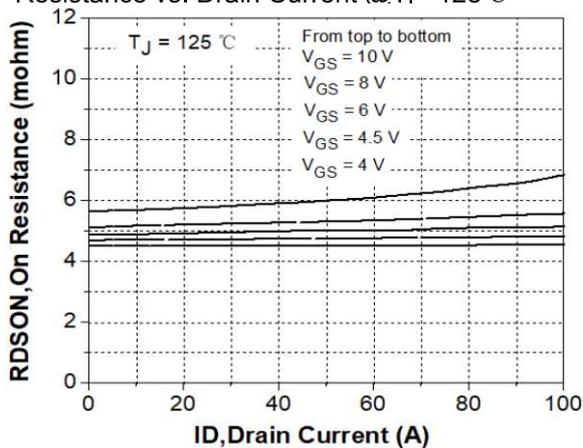


Fig10. Gate Charge Characteristics

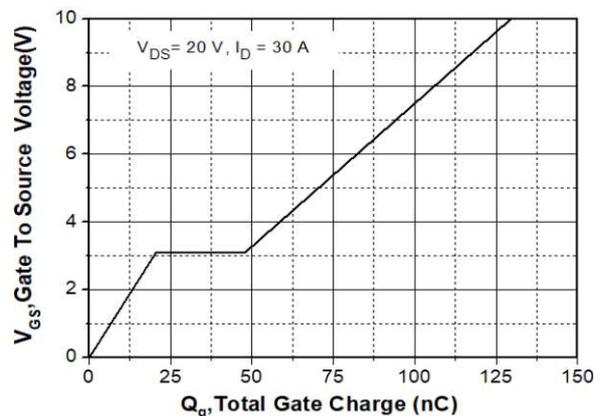


Fig11. Breakdown Voltage vs. Junction Temperature

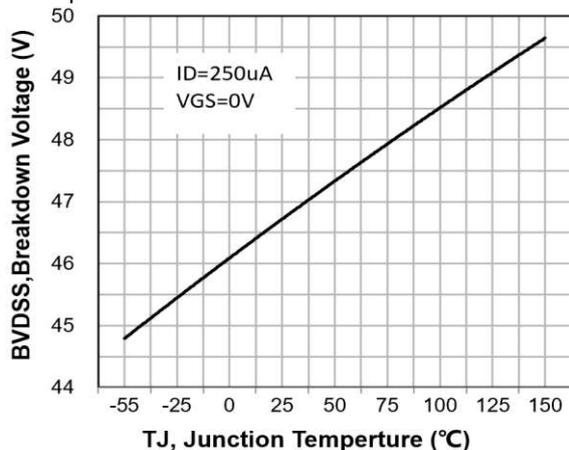


Fig12. Gate Threshold Voltage vs. Junction Temperature

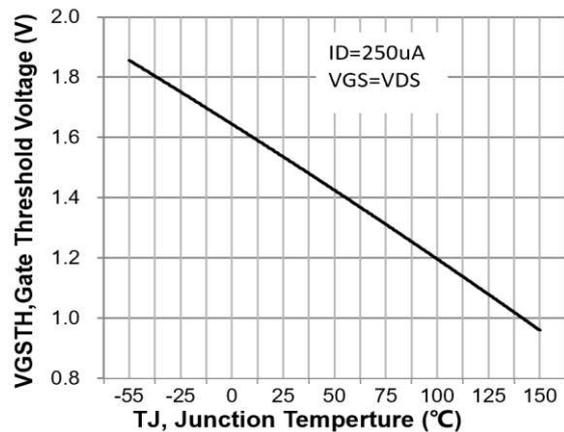


Fig13. Safe Operating Area

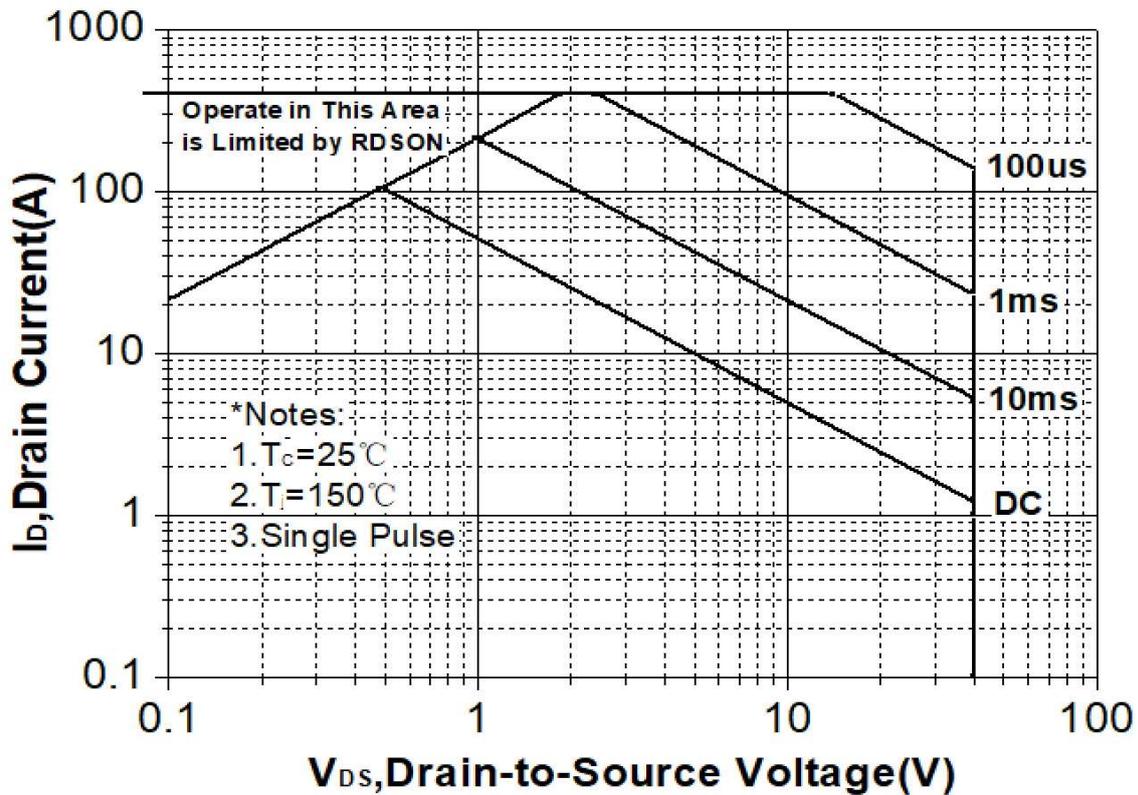


Fig14. Transient Thermal Response Curve

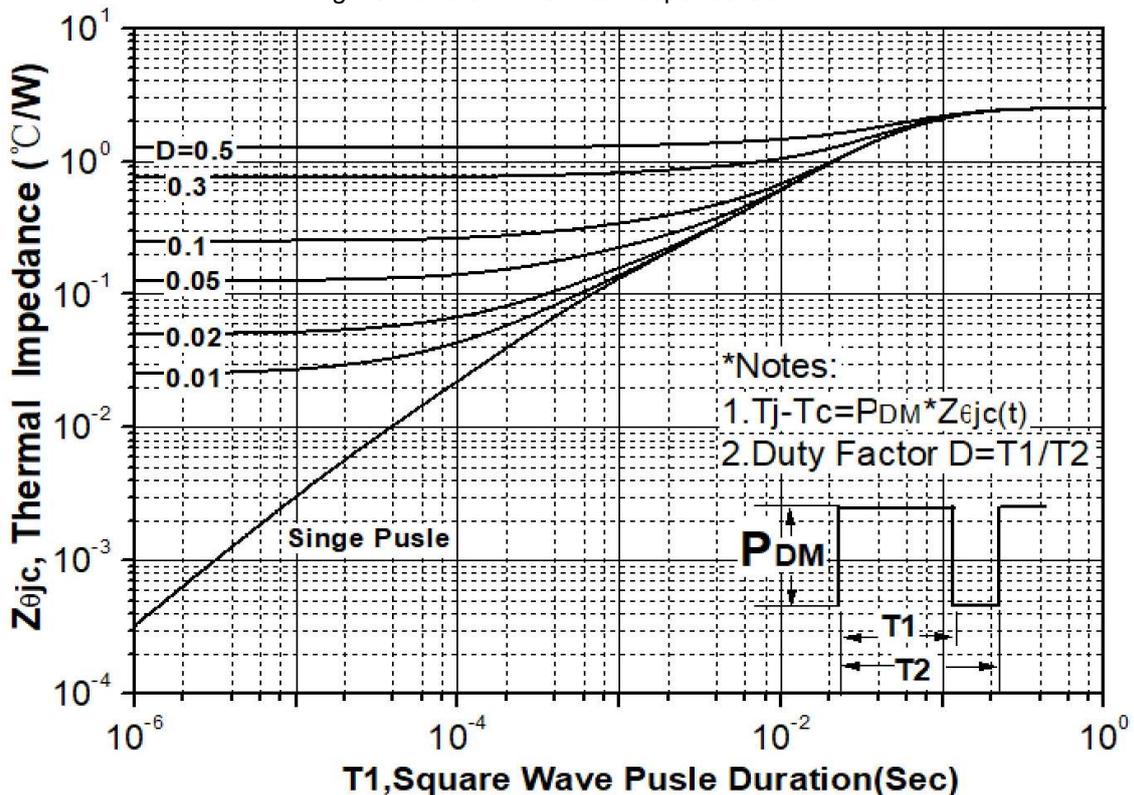


Fig15. On-Resistance Variation vs. Junction

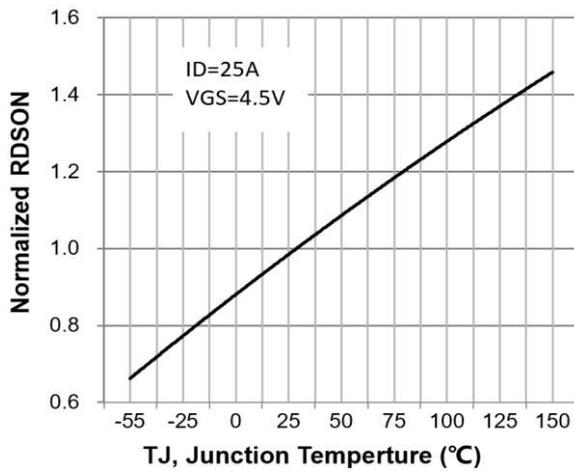


Fig16. Maximum Drain Current vs. Case Temperature

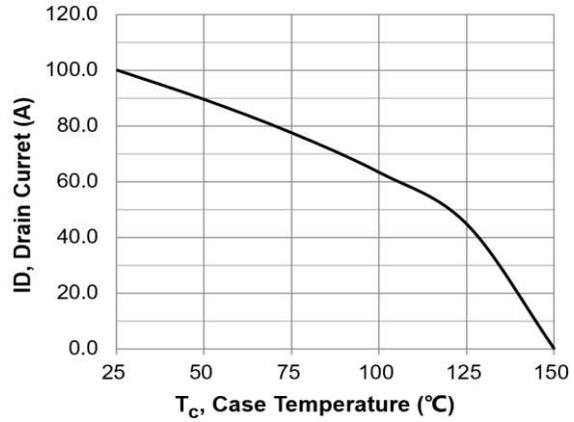


Fig17. Body Diode Forward Voltage vs. Reverse Drain Current

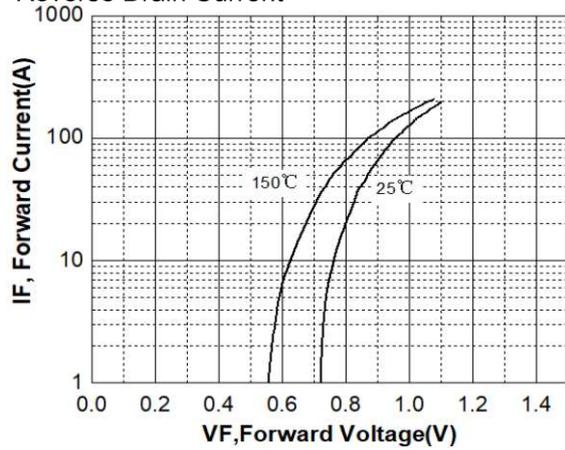
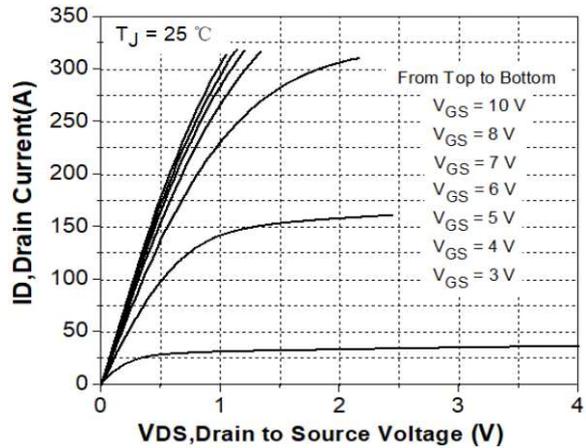
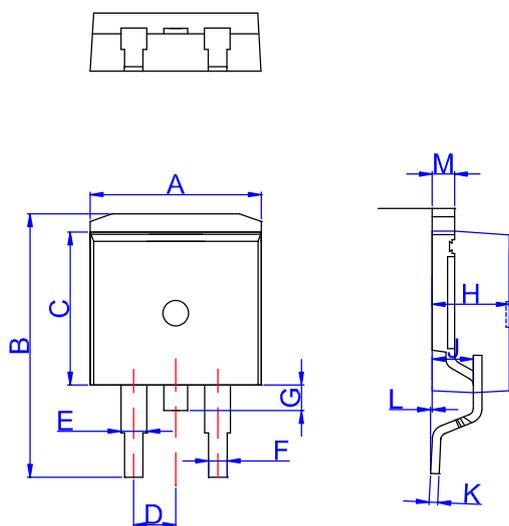


Fig18. Typical Output Characteristics@Tj=25°C



TO-263 Package Information



TO-263

| Ref. | Dimensions | | | | | |
|------|-------------|------|-------|--------|-------|-------|
| | Millimeters | | | Inches | | |
| | Min. | Typ. | Max. | Min. | Typ. | Max. |
| A | 9.90 | | 10.20 | 0.390 | | 0.402 |
| B | 14.70 | | 15.80 | 0.579 | | 0.622 |
| C | 9.4 | | 9.6 | 0.37 | | 0.378 |
| D | | 2.54 | | | 0.100 | |
| E | 1.20 | | 1.40 | 0.047 | | 0.055 |
| F | 0.75 | | 0.85 | 0.029 | | 0.033 |
| G | | | 1.75 | | | 0.069 |
| H | 4.40 | | 4.70 | 0.173 | | 0.185 |
| J | 2.30 | | 2.70 | 0.091 | | 0.106 |
| K | 0.38 | | 0.55 | 0.015 | | 0.022 |
| L | 0 | 0.10 | 0.25 | 0 | 0.004 | 0.010 |
| M | 1.25 | | 1.35 | 0.049 | | 0.053 |